Search Notes



Application/Control No.	Applicant(s)/Patent une Reexamination	der
10/780,938	HAYASHI, HIROKAZI	J
Examiner	Art Unit	
Paul Dinh	2825	

SEARCHED					
Class	Subclass	Date	Examiner		
716	4-5, 11, 18	8/26/2005	PD		
438	17-18	8/26/2005	PD		
324	658	8/26/2005	PD		
324	763,765	8/26/2005	PD		
257	48	8/26/2005	·PD		

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
above	8/26/2005	PD			
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	Subclass	Subclass Date			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST. IEEE	8/26/2005	PD	
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